

RECORDING TEST INFORMATION TO IDENTIFY A MEMORY ERROR LOCATION

ABSTRACT

5 A method of recording test information to identify a
location of errors in Integrated Circuits (ICs) includes
scanning a plurality of ICs with an input signal, each IC
having a plurality of data locations and comparing an
output response at each data location with an expected
10 value for the data location. The method also includes
storing an address in a buffer for each data location where
the response at the data location does not equal the
expected value corresponding to the data location.

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